



Artificial Intelligence for Medical Image Analysis

Guest Editor:

Prof. Dr. Anna Fabijańska

Institute of Applied Computer
Science, Lodz University of
Technology, 90-924 Lodz, Poland

Deadline for manuscript
submissions:

closed (10 May 2021)

Message from the Guest Editor

Dear Colleagues,

Deep learning approaches have demonstrated exceptional performance in the screening and diagnosis of many diseases. A further challenge of AI-driven solutions is to develop tools for a personalized disease assessment through deep learning models by taking advantage of their ability to learn patterns and relationships in data, utilizing massive volumes of medical images, and combining radiomics extracted from them with other forms of medical data.

With the above mentioned in mind, this Special Issue aims to promote the latest cutting edge AI-driven research in medical image processing and analysis. Of particular interest are submissions regarding computer-aided diagnosis and improvement of automated image interpretation. However, contributions concerning other aspects of medical image processing (including, but not limited to image quality improvement, image restoration, image segmentation, image registration, radiomics analysis) are also welcomed.

Dr. Hab. Anna Fabijańska
Guest Editor





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, Embase, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

Contact Us

Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)